


<b>Search Notes</b> 	<b>Application/Control No.</b> 10575425	<b>Applicant(s)/Patent Under Reexamination</b> PROUET ET AL.
	<b>Examiner</b> JOHN W POOS	<b>Art Unit</b> 4125

SEARCHED			
Class	Subclass	Date	Examiner
327	103	11/29/2007	JP
323	315	12/3/2007	JP

SEARCH NOTES		
Search Notes	Date	Examiner
terms used to constrain subclasses above: chip, different sized transistors, transconductance, differential input voltage	11/29/2007	JP
Inventor search in EAST and eDAN	12/3/2007	JP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner